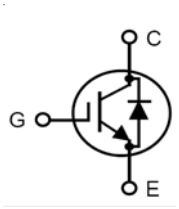
XPT™ 650V GenX4™ w/ Sonic Diode

IXXR110N65B4H1

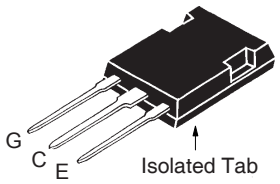
(Electrically Isolated Tab)

Extreme Light Punch Through
IGBT for 10-30kHz Switching



V_{CES} = 650V
I_{C110} = 70A
$V_{CE(sat)}$ ≤ 2.20V
$t_{fi(typ)}$ = 85ns

ISOPLUS247™



G = Gate C = Collector
E = Emitter

Symbol	Test Conditions	Maximum Ratings	
V_{CES}	T_J = 25°C to 175°C	650	V
V_{CGR}	T_J = 25°C to 175°C, R_{GE} = 1MΩ	650	V
V_{GES}	Continuous	±20	V
V_{GEM}	Transient	±30	V
I_{C25}	T_C = 25°C (Chip Capability)	150	A
I_{C110}	T_C = 110°C	70	A
I_{F110}	T_C = 110°C	48	A
I_{CM}	T_C = 25°C, 1ms	460	A
SSOA (RBSOA)	V_{GE} = 15V, T_{VJ} = 150°C, R_G = 2Ω Clamped Inductive Load	I_{CM} = 220 @ $V_{CE} \le V_{CES}$	A
t_{sc} (SCSOA)	V_{GE} = 15V, V_{CE} = 360V, T_J = 150°C R_G = 82Ω, Non Repetitive	10	μs
P_C	T_C = 25°C	455	W
T_J		-55 ... +175	°C
T_{JM}		175	°C
T_{stg}		-55 ... +175	°C
T_L	Maximum Lead Temperature for Soldering	300	°C
T_{SOLD}	Plastic Body for 10s	260	°C
V_{ISOL}	50/60 Hz, 1 Minute	2500	V~
F_C	Mounting Force	20..120/4.5..27	N/lb
Weight		5	g

Symbol	Test Conditions (T_J = 25°C, Unless Otherwise Specified)	Characteristic Values Min.	Typ.	Max.	
BV_{CES}	I_C = 250μA, V_{GE} = 0V	650			V
$V_{GE(th)}$	I_C = 250μA, V_{CE} = V_{GE}	4.0		6.5	V
I_{CES}	V_{CE} = V_{CES}, V_{GE} = 0V			25	μA
	T_J = 150°C			3	μA
I_{GES}	V_{CE} = 0V, V_{GE} = ±20V			±100	nA
$V_{CE(sat)}$	I_C = 110A, V_{GE} = 15V, Note 1		1.75	2.20	V
	T_J = 150°C		2.15		V

Features

- Silicon Chip on Direct-Copper Bond (DCB) Substrate
- Isolated Mounting Surface
- 2500V~ Electrical Isolation
- Optimized for 10-30kHz Switching
- Square RBSOA
- Short Circuit Capability
- Anti-Parallel Sonic Diode
- High Current Handling Capability

Advantages

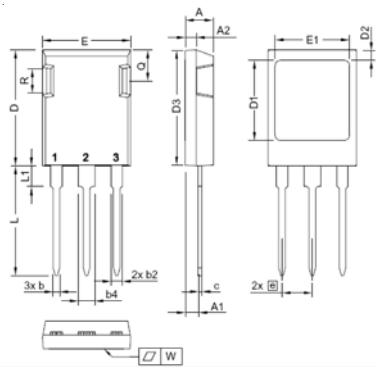
- High Power Density
- Low Gate Drive Requirement

Applications

- Power Inverters
- UPS
- Motor Drives
- SMPS
- PFC Circuits
- Battery Chargers
- Welding Machines
- Lamp Ballasts
- High Frequency Power Inverters

Symbol	Test Conditions (T_J = 25°C Unless Otherwise Specified)	Characteristic Values Min.	Typ.	Max.	
g_{fs}	I_C = 60A, V_{CE} = 10V, Note 1	24	40		S
C_{ies}	V_{CE} = 25V, V_{GE} = 0V, f = 1MHz		3650		pF
C_{oes}			440		pF
C_{res}			143		pF
$Q_{g(on)}$	I_C = 110A, V_{GE} = 15V, V_{CE} = 0.5 • V_{CES}		183		nC
Q_{ge}			32		nC
Q_{gc}			83		nC
$t_{d(on)}$	**Inductive load, T_J = 25°C**		38		ns
t_{ri}	I_C = 55A, V_{GE} = 15V		46		ns
E_{on}	V_{CE} = 400V, R_G = 2Ω		2.20		mJ
$t_{d(off)}$	Note 2		156		ns
t_{fi}			85		ns
E_{off}			1.05	1.90	mJ
$t_{d(on)}$	**Inductive load, T_J = 150°C**		34		ns
t_{ri}	I_C = 55A, V_{GE} = 15V		46		ns
E_{on}	V_{CE} = 400V, R_G = 2Ω		3.15		mJ
$t_{d(off)}$	Note 2		160		ns
t_{fi}			105		ns
E_{off}			1.40		mJ
R_{thJC}				0.33	°C/W
R_{thCS}			0.15		°C/W

ISOPLUS247 (IXXR) Outline



1 - Gate
2 - Collector
3 - Emitter

Dim.	Millimeter min	Millimeter max	Inches min	Inches max
A	4.83	5.21	0.190	0.205
A1	2.29	2.54	0.090	0.100
A2	1.91	2.16	0.075	0.085
b	1.14	1.40	0.045	0.055
b2	1.91	2.20	0.075	0.087
b4	2.92	3.24	0.115	0.128
c	0.61	0.83	0.024	0.033
D	20.80	21.34	0.819	0.840
D1	15.75	16.26	0.620	0.640
D2	1.65	2.15	0.065	0.085
D3	20.30	20.70	0.799	0.815
E	15.75	16.13	0.620	0.635
E1	13.21	13.72	0.520	0.540
e	5.45 BSC		0.215 BSC	
L	19.81	20.60	0.780	0.811
L1	3.81	4.38	0.150	0.172
Q	5.59	6.20	0.220	0.244
R	4.25	5.50	0.167	0.217
W	-	0.10	-	0.004

Reverse Sonic Diode (FRD)

Symbol	Test Conditions (T_J = 25°C Unless Otherwise Specified)	Characteristic Values Min.	Typ.	Max.	
V_F	I_F = 100A, V_{GE} = 0V, Note 1		1.7	2.3	V
	T_J = 150°C		1.8		V
I_{RM}	I_F = 100A, V_{GE} = 0V, T_J = 150°C		95		A
t_{rr}	$-di_F/dt$ = 1500A/μs, V_R = 300V		100		ns
R_{thJC}				0.70	°C/W

Notes:

1. Pulse test, t ≤ 300μs, duty cycle, d ≤ 2%.
2. Switching times & energy losses may increase for higher V_{CE}(Clamp), T_J or R_G.

Fig. 1. Output Characteristics @ T_J = 25ºC

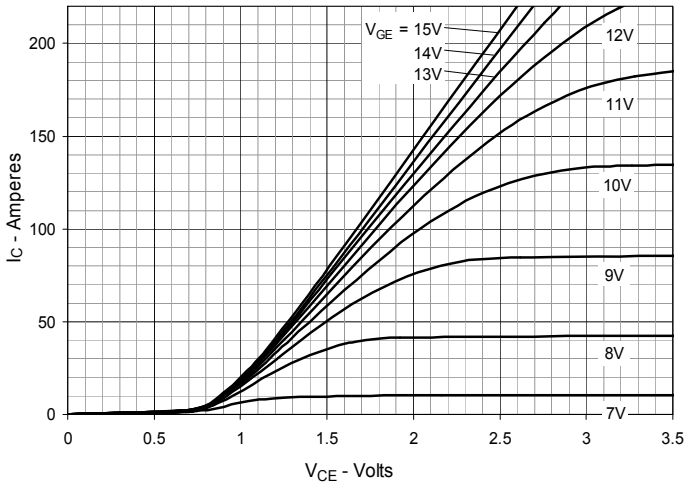


Fig. 2. Extended Output Characteristics @ T_J = 25ºC

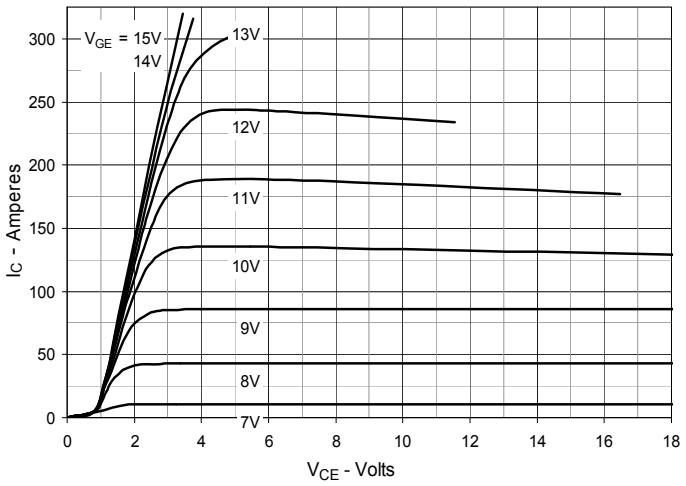


Fig. 3. Output Characteristics @ T_J = 150ºC

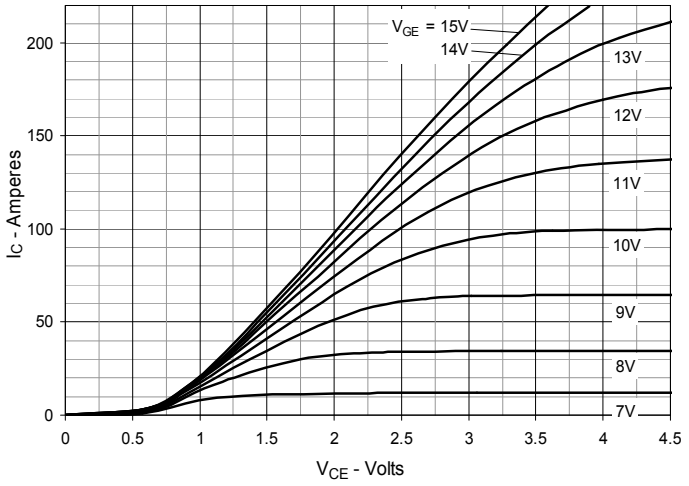


Fig. 4. Dependence of $V_{CE(sat)}$ on Junction Temperature

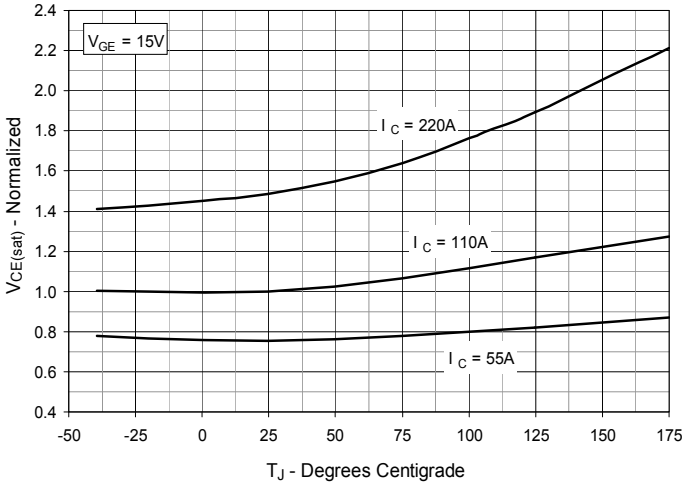


Fig. 5. Collector-to-Emitter Voltage vs. Gate-to-Emitter Voltage

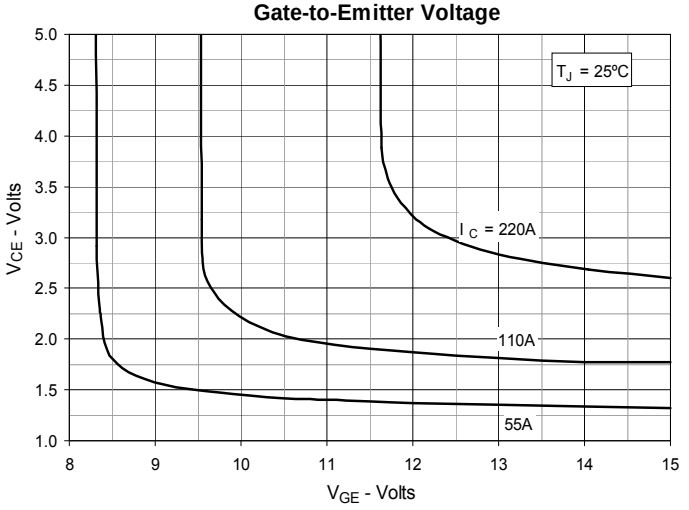


Fig. 6. Input Admittance

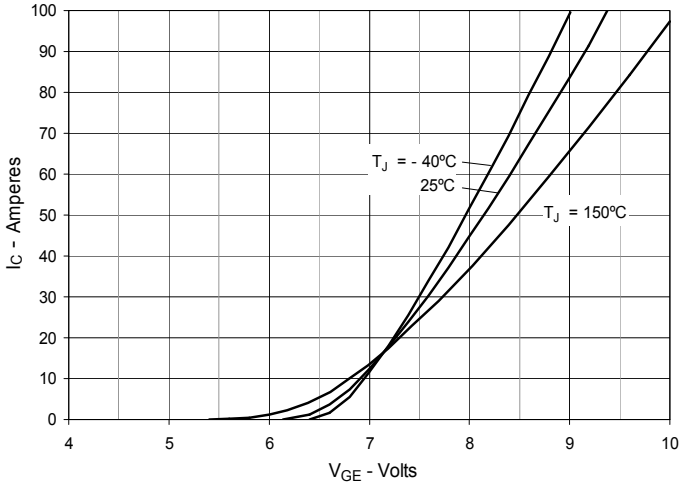


Fig. 7. Transconductance

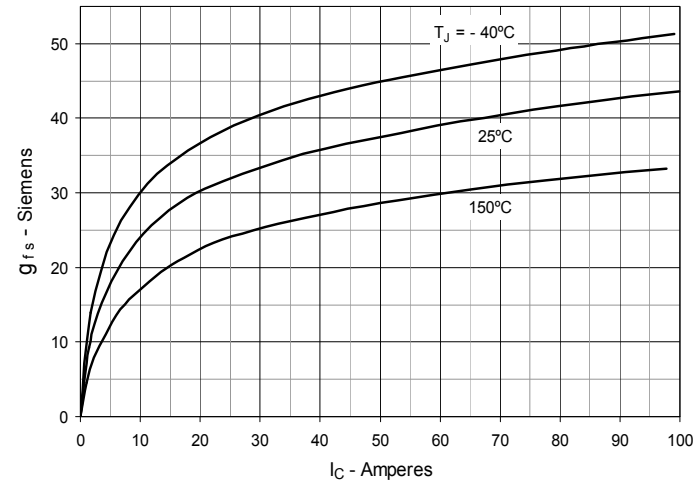


Fig. 8. Gate Charge

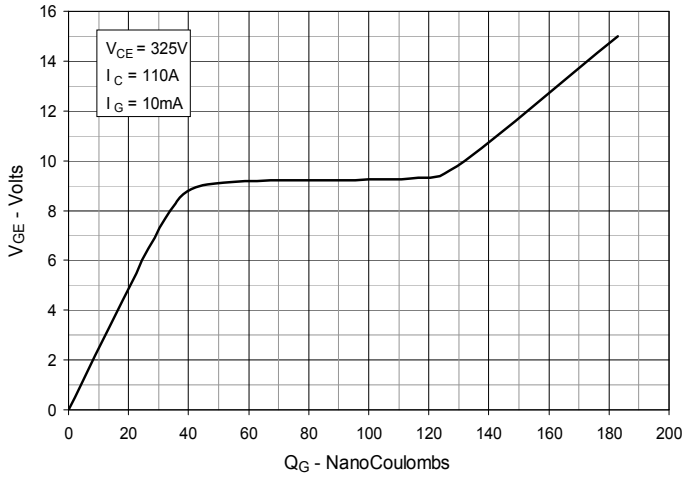


Fig. 9. Capacitance

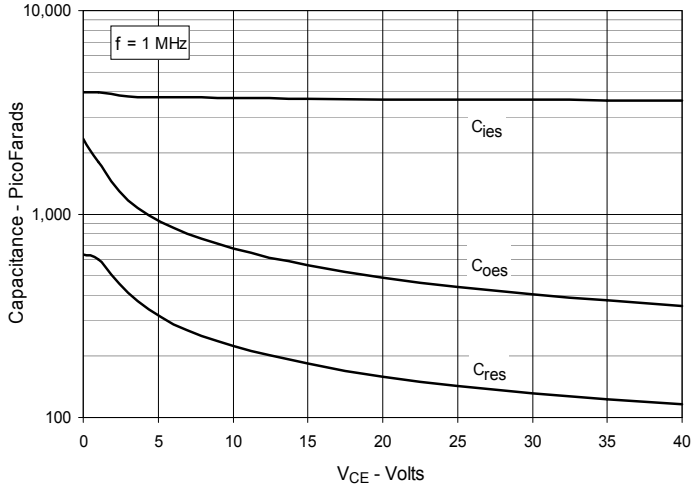


Fig. 10. Reverse-Bias Safe Operating Area

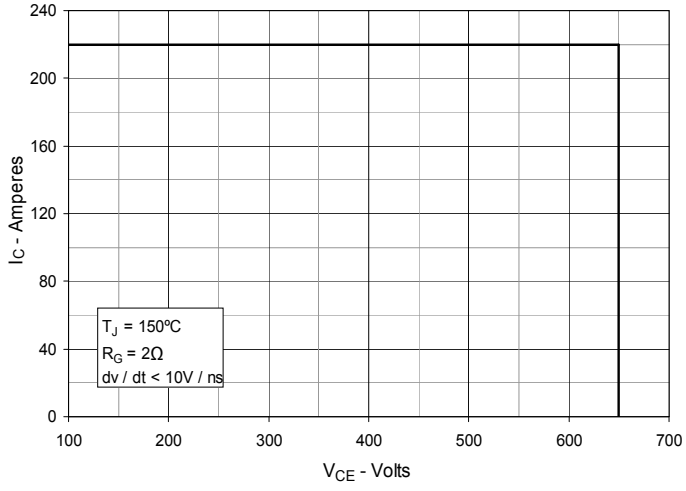


Fig. 11. Maximum Transient Thermal Impedance

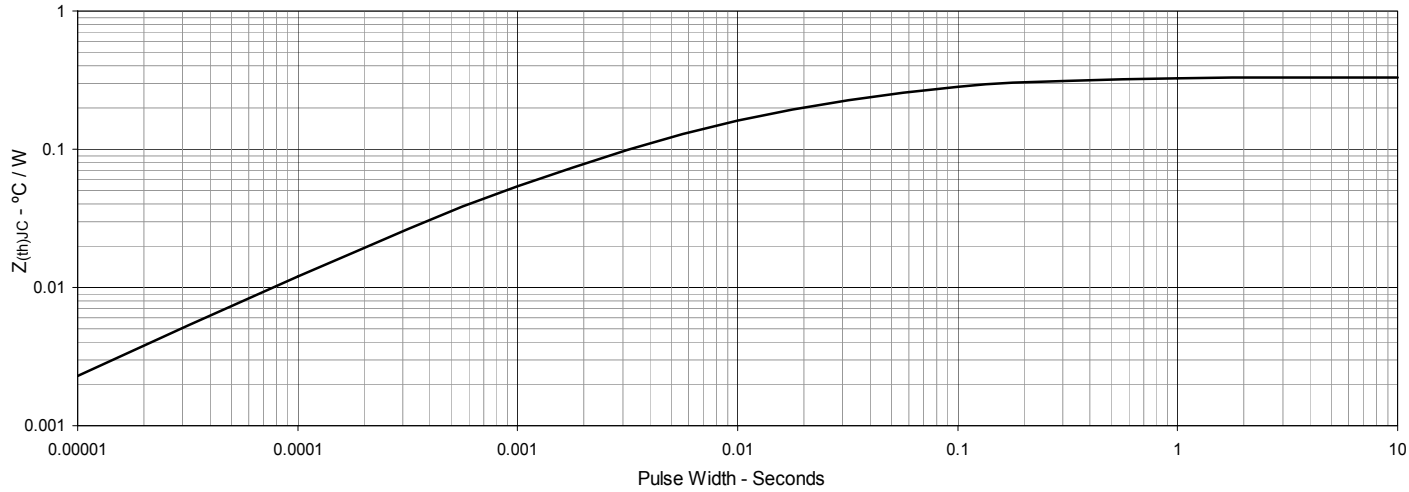


Fig. 12. Inductive Switching Energy Loss vs. Gate Resistance

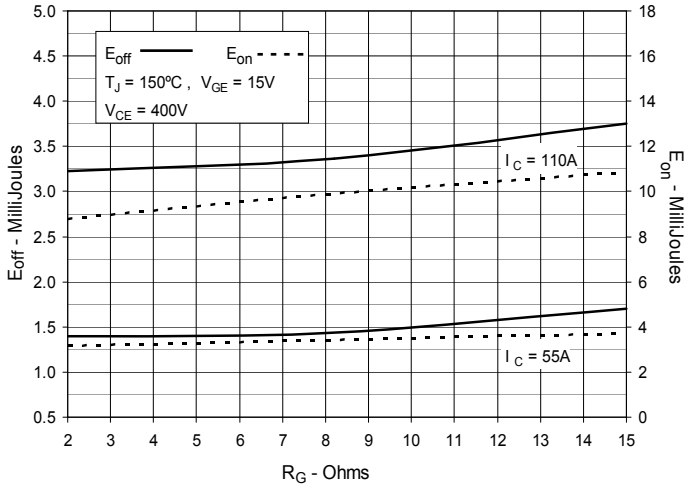


Fig. 13. Inductive Switching Energy Loss vs. Collector Current

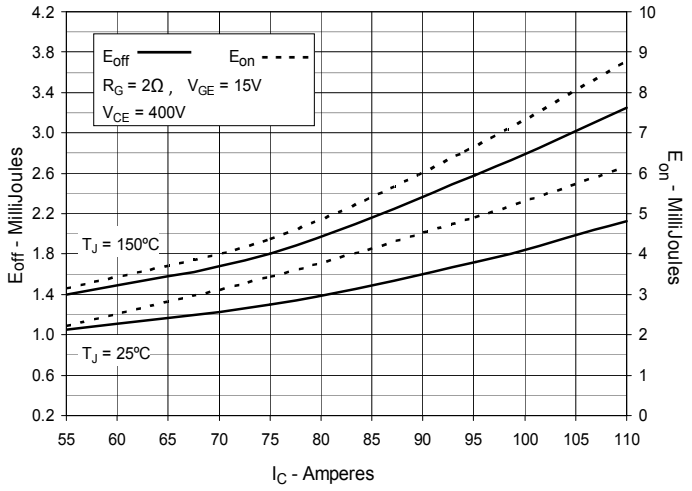


Fig. 14. Inductive Switching Energy Loss vs. Junction Temperature

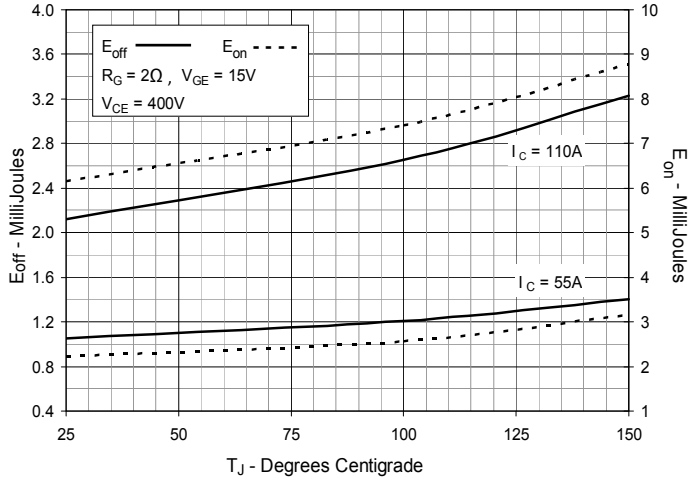


Fig. 15. Inductive Turn-off Switching Times vs. Gate Resistance

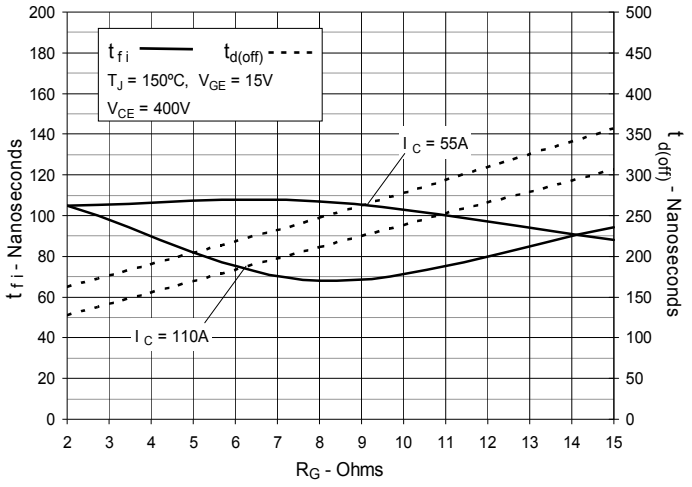


Fig. 16. Inductive Turn-off Switching Times vs. Collector Current

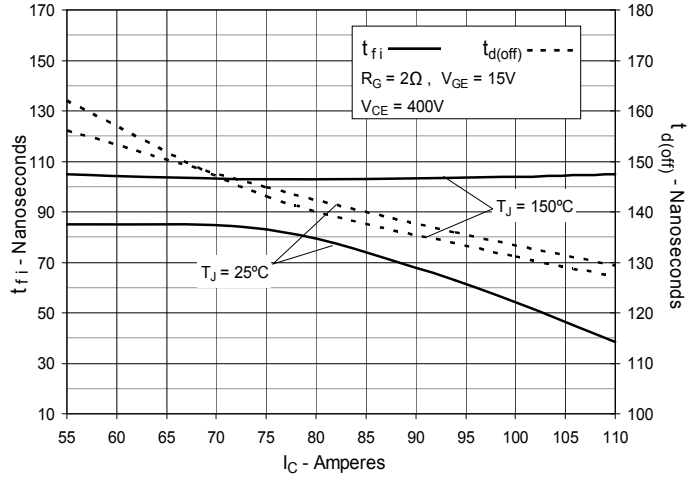


Fig. 17. Inductive Turn-off Switching Times vs. Junction Temperature

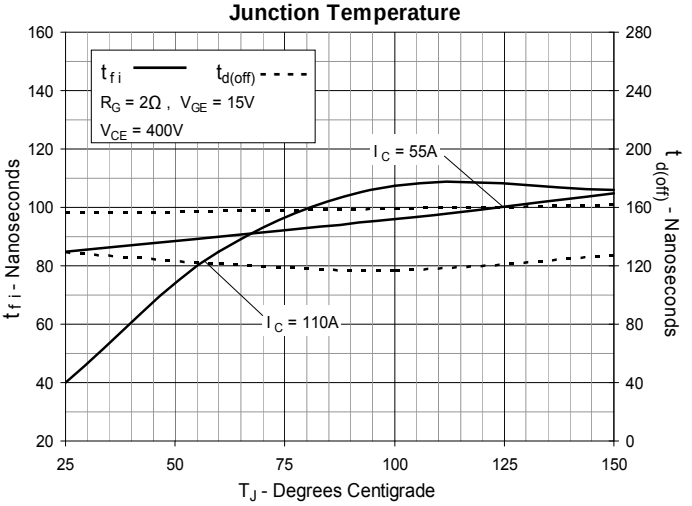


Fig. 18. Inductive Turn-on Switching Times vs. Gate Resistance

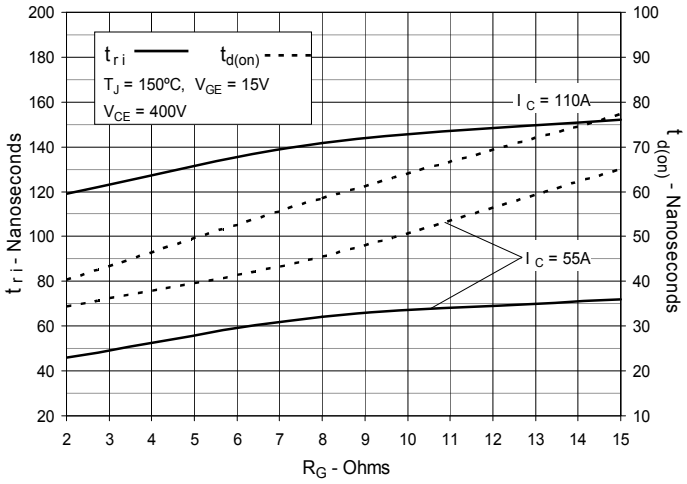


Fig. 19. Inductive Turn-on Switching Times vs. Collector Current

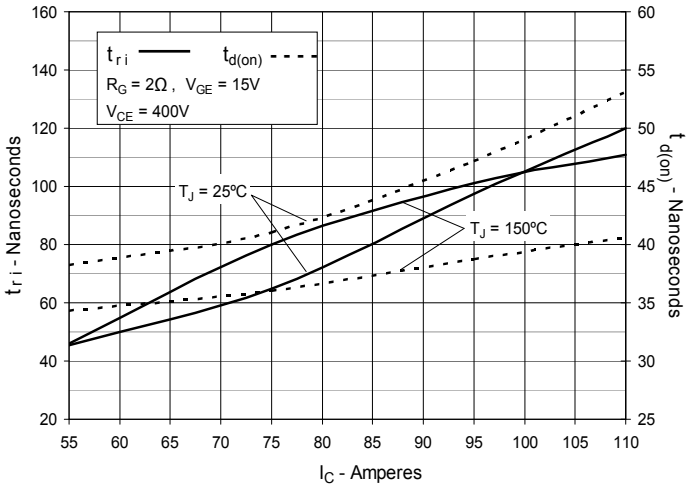


Fig. 20. Inductive Turn-on Switching Times vs. Junction Temperature

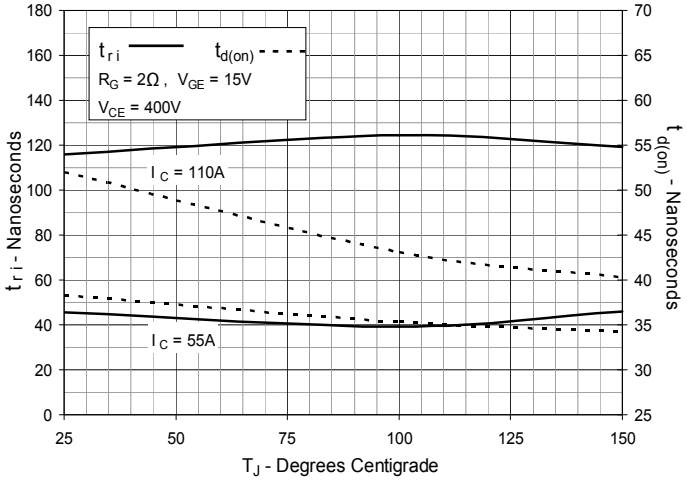


Fig. 21. Typ. Forward characteristics

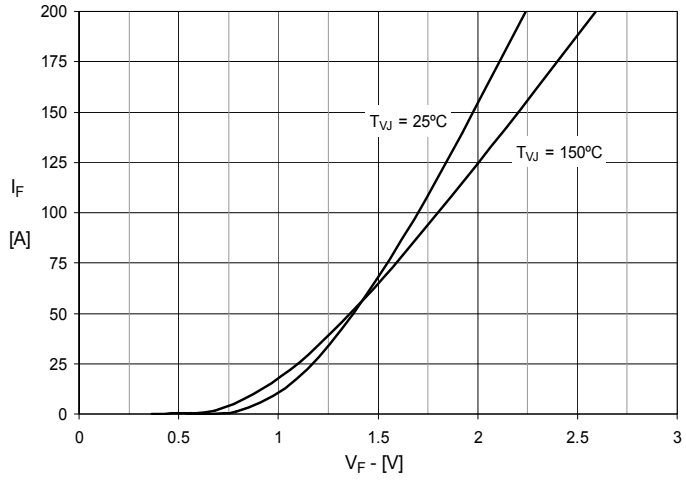


Fig. 22. Typ. Reverse Recovery Charge Q_{rr} vs. $-di_F/dt$

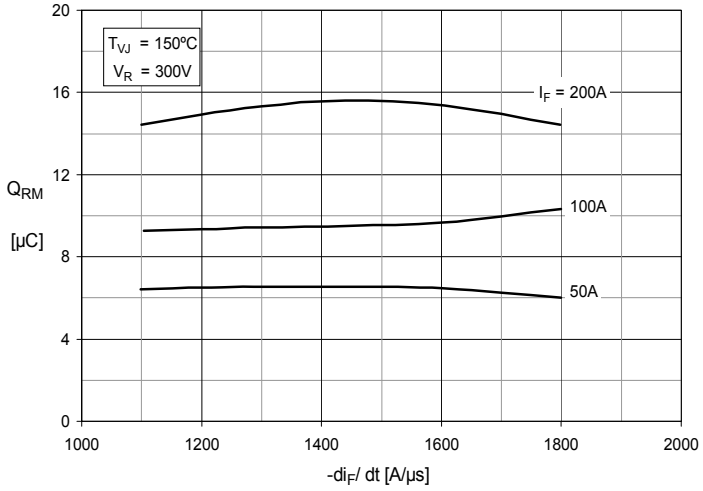


Fig. 23. Typ. Peak Reverse Current I_{RM} vs. $-di_F/dt$

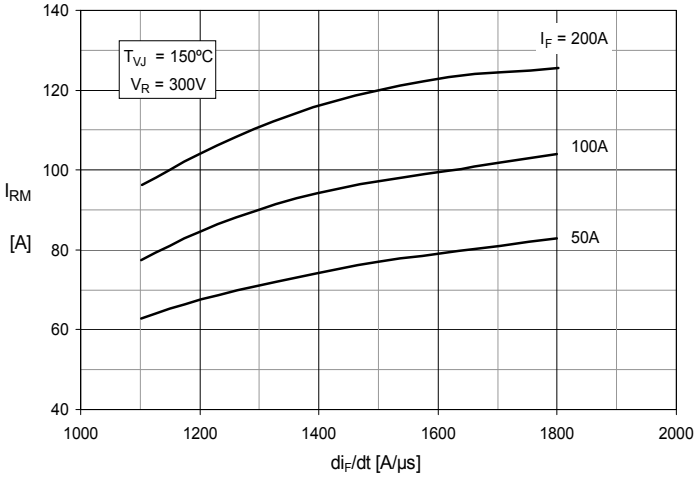


Fig. 24. Typ. Recovery Time t_{rr} vs. $-di_F/dt$

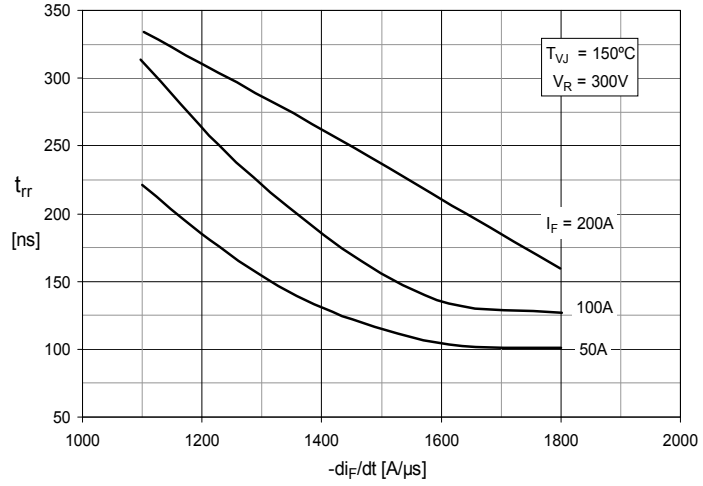


Fig. 25. Typ. Recovery Energy E_{rec} vs. $-di_F/dt$

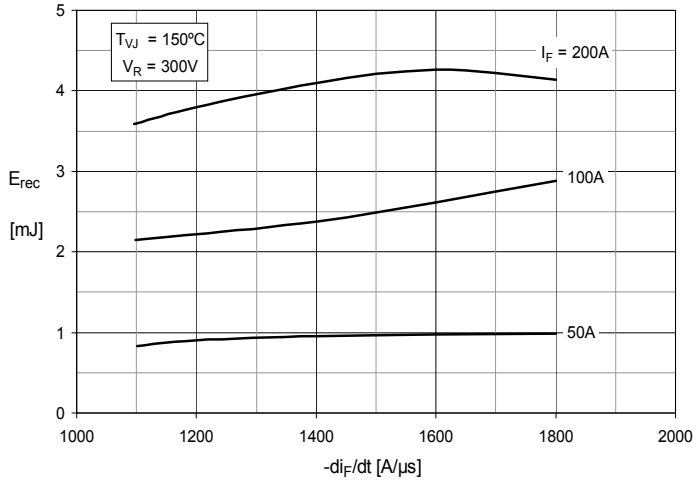


Fig. 26. Maximum Transient Thermal Impedance